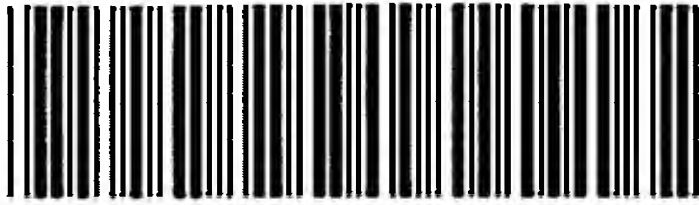


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/709,446	LEE ET AL.	
	Examiner	Art Unit	
	Matthew G. Kayrish	2627	

SEARCHED			
Class	Subclass	Date	Examiner
720	602	12/19/2005	MK
369	30.03	5/17/2006	MK
369	183 189	5/17/2006	MK
369	231-241	5/17/2006	MK
369	258.1	5/17/2006	MK
369	264-268	5/17/2006	MK
720	695 & 696	5/17/2006	MK
720	698	5/17/2006	MK
720	700	5/17/2006	MK

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
360	133	5/17/2006	MK
369	30.03	5/17/2006	MK
EAST (USPG-PUB)		5/17/2006	MK

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (US-PGPUB, USPAT, USOCR) (See Attached Search History)	12/19/2005	MK
EAST (EPO, JPO, DERWENT, IBM_TDB) (See Attached Search History)	12/19/2005	MK
EAST (US-PGPUB, USPAT, USOCR) (See Attached Search History)	12/23/2005	MK
EAST (USPG-PUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB) (See Attached Search History)	5/17/2006	MK